List of research papers written by our customers using our EUV mirrors and soft x-ray mirrors

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NTT ADVANCED TECHNOLOGY CORPORATION (NTT-AT) has been providing EUV mirrors and soft x-ray mirrors to industrial and academic customers for more than 20 years. The customers are using our optics for many kinds of applications such as high order harmonics generation (HHG), attosecond science, plasma physics, and astronomy. In this document, we present customers' publications from 2010 to 2025 for your references. You can also find our product detail from the link below;
https://keytech.ntt-at.co.jp/en/xray/prd_3004.html

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[5] Y. Hori and S. Gonda, "Error investigation for SI traceable pitch calibration of one-dimensional grating by grazing-incidence small-angle X-ray scattering," Measurement (2024)

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